

Notice of References Cited	Application/Control No. 10/522,495		Applicant(s)/Patent Under Reexamination INNEMAN ET AL.	
	Examiner Allen C. Ho		Art Unit 2882	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,811,965 B2	11-2004	Vodovotz et al.	435/1.2
*	B	US-2004/0131147 A1	07-2004	Bowen et al.	378/043
*	C	US-2003/0081731 A1	05-2003	Souchay et al.	378/154
*	D	US-6,307,917 B1	10-2001	Shimizu et al.	378/145
*	E	US-6,266,392 B1	07-2001	Fujinawa et al.	378/149
*	F	US-5,455,849	10-1995	Logan et al.	378/154
*	G	US-5,231,655	07-1993	Wei et al.	378/147
*	H	US-5,164,974	11-1992	Kariya et al.	378/34
*	I	US-4,429,953	02-1984	Zehnpfennig et al.	359/846
*	J	US-4,125,776	11-1978	Tosswill et al.	378/149
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U	H. H. Otto and W. Hofmann, J. Appl. Cryst. 29, 495-497 (1996).				
	V	B. D. Cullity and S.R. Stock. Elements of X-Ray Diffraction, third edition (New Jersey: Prentice Hall, 2001), p. 194-197, 270-272.				
	W					
	X					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.